

# 2D imaging X-ray spectrometer on WEST: results and technical challenges

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#### INTRODUCTION

- A 2D X-ray imaging crystal spectrometer (XICS) was installed on WEST [1]
- A remote-controlled rotating stage allows to choose one of 3 crystals, focusing on:
- Intrinsic FeXXV K-alpha spectrum (~1.86 A) (intrinsic Fe, low S/N)
- Injected Ar XVII K-alpha spectrum (~3.97 A) (injected Ar, good S/N)
- Injected ArXVIII Lyman-alpha spectrum (~3.73 A) (for high Te, low S/N otherwise)

Designed to indirectly measure:

Te (line ratio), Ti (Doppler broadening), vi (Doppler shift)

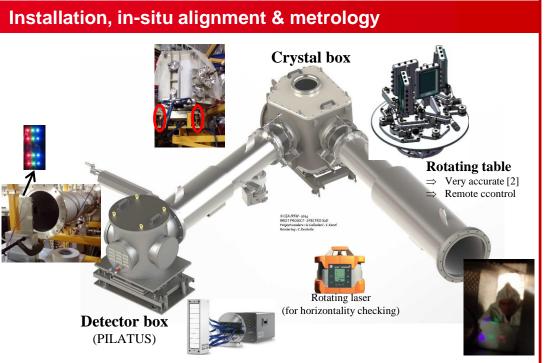
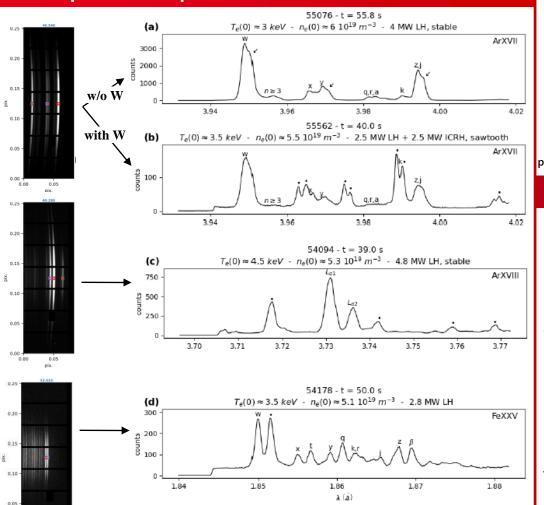


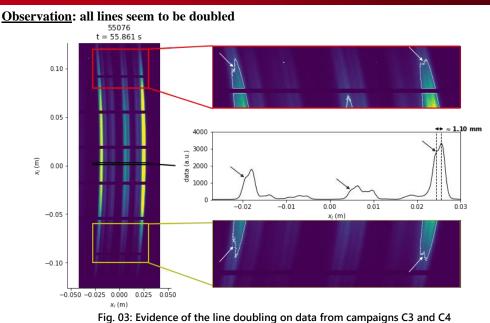
Fig. 01: Sketch of the XICS set-up on WEST and alignment apparatus. The detector camera is located tangentially to a best fit of the three crystals' Rowland circles. Horizontality was checked with a rotating laser, micro-screws were used for fine-positioning of the boxes

and of each crystal to determine the best focalization of a slit source, and lines of sight were finally embodied by retro-lighting using a panel of diodes on a mock detector frame.

## First experimental spectra and extra lines from W



#### Lines doubling

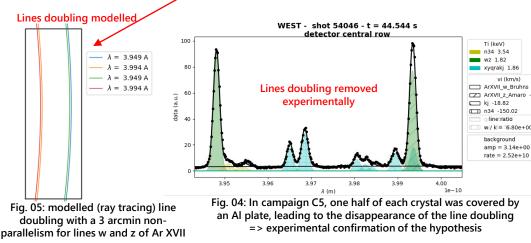


Context: crystals manufactured in 2 halves, glued side by side on a common support.

**<u>Hypothesis</u>**: parallelism between inner lattice and optical surface = accuracy of cut. Tolerance on each half cumulates to a non-negligible discrepancy (spectral shift) between the spectra focused by each crystal half => 2 shifted spectra superimposed.

id	mat.	thick. $(\mu m)$	$\operatorname{mesh}$	cut (Miller)	$\overset{d}{(\dot{A})}$	parallel. (arc min)	$\dim. \\ (mm xmm)$	$\operatorname{curv.}(m)$	$\lambda_{ref} \ \dot{(A)}$	$egin{aligned} eta(\lambda_{ref})\ ( ext{deg.}) \end{aligned}$	$lpha_{ref}$ (deg.)
Ar XVII Ar XVIII Fe XXV	Quartz Quartz Ge	197 197 176	hex. hex. cubic	$(1,1,-2,0) \\ (1,0,-1,2) \\ (4,2,2)$	2.454 2.279 1.155	$\underbrace{\leq 1.5}_{\leq 1.5}_{\leq 1.0}$	$\begin{array}{c} (2x40)x100 \\ (2x40)x100 \\ 40x(2x53) \end{array}$	2.743 2.743 2.743	$3.96 \\ 3.75 \\ 1.86$	53.8 55.3 53.6	1.3405 -101.0 -181.9705





## **CONCLUSION and Perspectives**

#### **Conclusion:**

- Spectrometer installed, aligned, operated
- Spectra as expected except:
  - W extra lines (identified by another team in [3])
  - Lines doubling (explained in this poster)

Short term / ongoing efforts, using tofu [4]:

Fig. 02: (left column) Examples of typical 2d spectra images on the detector for each crystal (right column) typical associated 1d spectra (a) and (b) Ar XVII spectra, with and w/o W lines (dots) - line doubling indicated by arrows (c) Ar XVIII spectrum, with W pollution (d) FeXXV spectrum

Extra lines from W, identified in [3], are visible in plasma conditions that remain to be systematically characterized.

 $\Rightarrow$  Induce spectral pollution (short-term), but vehicles extra information (long-term)

- Determination of an optimal set of operation parameters
- **Optimization of fitting routines (inc. doubling)**
- Accurate 3D modelling accounting for observations (non-parallelism, vignetting...)
- Automated production of line-integrated proxys of Te and Ti issued
- Synthetic diagnotics

#### Longer term:

- Better understanding of injected Ar behavior (transport...)
- Triple inversion algorithms to get local (Te, Ti, vrot) fields [5]
- Cross-validation with other diagnostics (ECE, multi-energy SXR camera...)
- **Replace crystals with single-piece**

#### References

[1] D. Vezinet et al, ECPD conference; Lisboa, 2019, poster P3.6 [2] G. Colledani patent number 1653710 from the 27th April 2016 [3] J E Rice et al 2021 J. Phys. B: At. Mol. Opt. Phys. 54 095701 [4] D. Vezinet et al, Nuclear Fusion, 56, 2016